

MJ33 Bright field and Dark field Metallurgical microscope



Metallurgical microscope MJ33 in bright field & dark field is a microscope used in industrial inspection, equipped with bright/dark field objectives, wide field eyepiece and polarizing observation device. The reflective and transmitted illumination system adopts Kohler illumination with clear field of view. It can be used for the observation of semiconductor silicon wafer, LCD substrates, circuit boards, and other kinds of powder solid transparent or opaque industrial test specimen. This metallurgical microscope is an ideal instrument for research of biology, metallurgy, mineralogy, precision engineering and electronics engineering, etc.

Eyepiece	Wide field WF10X(field number Φ 22mm)
Objective	Infinity plan achromatic bright or dark field long work distance. (no cover glass)
	PL L5X/0.12 B. D (Work distance): 9.7 mm
	PL L10X/0.25 B. D (Work distance): 9.3 mm
	PL L20X/0.40 B. D (Work distance): 7.2 mm
	PL L40X/0.60 B. D (Work distance): 3.0 mm
Eyepiece tube	Trinocular, 30°inclined, (Built in analyzer and switching freely)
Epi- illumination system	12V 50W halogen lamp, brightness adjustable
	Built-in field diaphragm, aperture diaphragm and filter switching device.
	Push-pull type analyzer and polarizer
	Yellow, blue, green filter and frosted glass
Focus system	Coaxial coarse/fine focus system, with tension adjustable and limit stopper, minimum division of fine focusing: 2 μ m.
Nosepiece	Quintuple (Fixed nosepiece with backward inclined)
Stage	Double layer mechanical movable stage (size: 210mmX140mm, moving range: 75mmX50mm)
	Glass plate 97x76mm
Transmitted illumination system	Abbe condenser NA. 1.25 up and down adjustable
	Blue filter and frosted glass
	Condenser for illumination with halogen lamp (with field diaphragm)
	12V 30W halogen lamp, brightness adjustable
Adapter	1X C-mount adapter